

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/550,273	OSAWA, HIROSHI	
Examiner		Art Unit		Page 1 of 1
Kevin M. Bernatz		1794		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,899,959	05-2005	Bertero et al.	428/611
*	B	US-2002/0122960	09-2002	Hanawa et al.	428/694.0TS
*	C	US-5,147,732	09-1992	Shiroishi et al.	428/668
*	D	US-2006/0046102	03-2006	Bian et al.	428/828.1
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Shiroishi, Y., Matsuda, Y., Yoshida, K., Suzuki, H., Ohno, T., Tsumita, N., Ohura, M., and Hayashi, M., IEEE Trans. Mag., 24(6), 1988, 2730 - 2732.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.